Chinese Chemical Letters Vol. 15, No. 12, pp 1505-1508, 2004 http://www.imm.ac.cn/journal/ccl.html

# New Photoluminescence Phenomena of Ge/SiO<sub>2</sub> Glass Synthesized by Sol-gel Method

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**Abstract:** New Ge/SiO<sub>2</sub> glasses have been synthesized by heating the GeO<sub>2</sub>/SiO<sub>2</sub> dry gels under H<sub>2</sub> gas at 700 °C. The resulting fluorescence spectra show that this kind of Ge/SiO<sub>2</sub> glasses emit strong photoluminescence at 392 nm (3.12 eV), medium strong photoluminescence at 600 nm (2.05 eV) and weak photoluminescence at 770 nm (1.60 eV) respectively. Possible photoluminescence mechanisms are also discussed based on the results of X-ray diffraction (XRD) and X-ray photoelectron spectra (XPS).

Keywords: Ge/ SiO2 glasses, Ge nanocrystals, photoluminescence, sol-gel method.

Ge-doped SiO<sub>2</sub> glasses have been studied extensively in recent years due to their special significance in microelectronics and optic electronics<sup>1</sup>. Maeda *et al.* prepared Ge microcrystals embedded in SiO<sub>2</sub> glassy matrices by rf-magnetron cosputtering method <sup>2</sup>, and observed 570 nm (2.16 eV) photoluminescence at room temperature. Nagomi *et al.* prepared Ge/SiO<sub>2</sub> glasses by sol-gel method and observed 510-680 nm (2.42-1.81 eV) broad band photoluminescence at 77 K temperature <sup>3</sup>. Min *et al.* prepared Ge crystals embedded in SiO<sub>2</sub> film, and observed 680 nm (1.8 eV) photoluminescence at room temperature<sup>4</sup>. However till so far, there have no reports about Ge/SiO<sub>2</sub> glasses with photoluminescence of more than two colour bands. For this reason, the application of Ge/SiO<sub>2</sub> glasses in light-storage and other fields was limited.

In this paper, we have synthesized a new kind of luminescent  $Ge/SiO_2$  glasses by sol-gel method plus  $H_2$  reduction. When excited by UV light, this material can give off luminescence at three bands. Its property and photoluminescence mechanism based on XRD and XPS results were discussed.

## **Results and Discussion**

 $GeO_2/SiO_2$  dry gels were prepared by method described previously<sup>5</sup>. Then these dry gels were heated at 700°C in a fused silica tube under the flow of 70% H<sub>2</sub> and 30% Ar.

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The gels were held at 700°C for 3 hours to produce Ge/SiO<sub>2</sub> nanometer crystal glasses. The photoluminescence experiment (Figure 1) showed that sample A, which was reduced by H<sub>2</sub>, emitted three luminescence peaks at 392 nm, 600 nm, and 770 nm respectively. This means that the sample A can produce violet, orange and red light under UV excitation of 246 nm. The unreduced sample B shows no obvious lumenescence peak. Thus, after reduction under H<sub>2</sub>, sample A owned a special luminescent property compared with unreduced sample B.

XRD and XPS techniques are always used to study the change of property of the material. In order to analyze the photoluminescence phenomena described above for sample A and B, we employed XRD and XPS to investigate the structure of sample A and B. Figure 2 shows the XRD experiment results. For sample A (curve A in Figure 2), there are obvious crystalline diffraction peaks. The 2θ positions of 27.22°, 45.24°, 53.60°, 72.66°, 83.70° correspond to cubic structure of Ge (111), Ge (220), Ge (311), Ge (331), Ge (422) planes. The 20 positions of 20.34° and 26.06° correspond to hexagonal structure of  $GeO_2$  (100) and (101) planes. These results indicate there were Ge and  $GeO_2$  crystals in sample A. Also curve B in Figure 2 shows that sample B are excited mainly as amorphous GeO2. Even in the heating process, there are very few GeO2 crystals, corresponding to hexagonal structure of  $GeO_2$  (100) and (101) planes, no Ge crystals existing in the sample B.

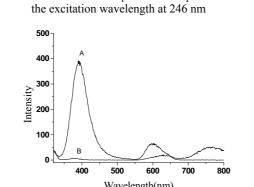
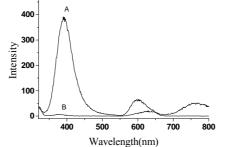
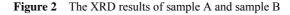
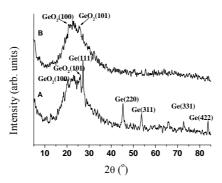


Figure 1

The fluorescence spectra of sample A and sample B,



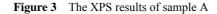




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The XPS results of sample A are shown in **Figure 3**. After dealing with the results, the spectrum of sample A can be separated to 3 Gaussian peaks centered at 29.24 eV, 31.41 eV and 32.61 eV, corresponding to 3d peaks of Ge, GeOx and GeO<sub>2</sub>, and indicate the existence of germanium and germanium oxides in sample  $A^6$ , showing some of germanium oxides were reduced to germanium. While for sample B (**Figure 4**), since it was not reduced by H<sub>2</sub>, there is only 3d peak of GeO<sub>2</sub>, with no indication of the germanium crystal existence. These XPS results are consistent with the XRD results.

The phenomenon observed here that Ge/SiO<sub>2</sub> glasses give off three bands of different color luminescence has never been reported before. We deduce this luminescent property may be due to the existence of Ge nanocrystals in the glass sample<sup>3</sup>. These various-size crystals are under three-dimensional quantum confinement. The relation of their crystal size and the energy corresponding to the luminescence light is  $R=\pi h/\sqrt{2m(E-Eg)}^{7}$ , where m is reduced mass of an electron-hole pair, Eg is an optical band gap of bulk crystalline Ge (which is 0.66 eV here <sup>8</sup>), E is the lowest energy of the electron-hole pair (which corresponds to the energy of the luminescence peak position). From this formula, the crystal sizes of the Ge can be deduced about 10 nm. As a comparison, we found that the samples made in faster H<sub>2</sub> reduction process and bigger crystal sizes did not show this luminescent property.



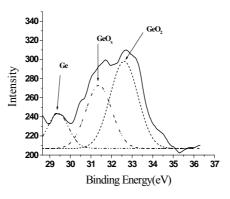
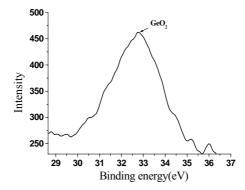


Figure 4 The XPS results of sample B.



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On the other hand, the special luminescent property of sample A may be due to the germanium oxygen deficient centers (GODCs) existing in the  $Ge_x/Si_x/O_x$  system too <sup>9</sup>. From the results of XRD and XPS experiments, it can be known that the crystals in sample A are Ge, GeO<sub>x</sub> and GeO<sub>2</sub>, so oxygen in the crystal of sample A is very deficient, causing sample A to emit the photoluminescence with the peak at 392 nm (violet light) which corresponds to GeO indicating that the translated from triplet excited state to singlet ground state, emitting violet light <sup>10</sup>. The photoluminescence with the peak at 600 nm (yellow light) may be caused by the germanium oxide-related defects located at the interface between the germanium nanocrystals and the matrix, which is consistent with the samples made by magnetron cosputtering method <sup>11</sup>. The mechanism for 770 nm (red light) photoluminescence is not very clear yet.

In summary, the Ge/SiO<sub>2</sub> glasses were synthesized by the sol-gel method with  $H_2$  reductione4 and these glasses have a special luminescent property. The results of the fluorescence spectra show that the Ge/SiO<sub>2</sub> glasses have three luminescent bands with the peaks at 392 nm, 600 nm and 770 nm respectively, that is to say, the Ge/SiO<sub>2</sub> glasses can produce violet, orange and red light at the same time. According to the data of the XRD and XPS, the mechanism of luminescence has been discussed, but the exact reason needs further investigation.

#### Acknowledgment

This work was financially supported by Natural Science Foundation of Jiangsu Education Department (Grant No. 2000LHZOOOOSJI) and the National Natural Science Foundation of China (No. 29973015)

### References

- 1. A. Dutta, Appl. Phys. Lett., 1996, 68 (9), 1189.
- 2. Y. Maeda, N. Tsukamoto, and Y. Yazawa, Appl. Phys. Lett., 1991, 59 (24), 3168.
- 3. M. Nogami, Y. Abe, Appl. Phys.Lett., 1994, 65 (20), 2545.
- K. S. Min, K. V. Shcheglov, C. M. Yang, and H. A. Atwater, *Appl. Phys. Lett.*, **1996**, 68 (18), 2511.
- 5. Y. H. Zhou, Y. Y. Feng, H. Y. Lu, Spectroscopy and Spectral Analysis, 2000, 20 (1), 23.
- J. Q. Wang, W. H. Wu, D. M. Feng, X-ray photoelectron spectroscopy, Beijing, National Defence Industry Press, 1992, 533.
- 7. L. E. Brus, IEEE J. Quantum Electron, 1986, 22, 1909.
- 8. G. G. Macfarlane, T. P. Mclean, et al., Phys. Rev., 1957, 108 (6), 1377.
- 9. M. Fujimaki, and Y. Ohki, J. Appl. Phys., 1997, 81 (3), 1042.
- 10. Y. X. Jie, X. Wu, C. H. Huan, A. T.S. Wee, Y. Guo, et al., Sur. Interface Anal., 1999, 28, 195.
- 11. Y. M. Dong, J. Chen, N. Y. Tang, et al., Chin. Sci. Bull., 2001, 46(6), 525.

Received 13 January, 2004

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